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FRADE	MARK			U.S. PATENT DOCUMENTS	741, 27, 2005				
*Examiner Initial		Document Number	Date	None		Class	Subclass	Filing Da	
Ab	AA	5,604,159	02/97	Cooper, et al.					
AL	AB	6,277,708	08/01	Bothra, et al.					
All	/ AC	6,136,701	10/00	Shin					
Re	AD	6,291,286	09/01	Hsiao					
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K	AA.	5,539,229	07/96	Noble, Jr., et al.							
All	AB	5,214,603	05/93	Dhong, et al.							
AL	AC	4,604,162	08/86	Sobezak							
Ale	AD	5,391,911	02/95	Beyer, et al.							
A	? AE	5,763,931	06/98	Sugiyama							
X	AF	5,599.724	02/97	Yoshida							
X	AG	5,846,854	12/98	Giraud, et al.							
X	AH	5,011,783	04/91	Ogawa, et al.							
XD	Al	4,700,461	10/87	Choi, et al.	Choi, et al.						
XU	N	5,608,248	03/97	Ohno							
X	AK	6,091,129	07/00	Cleeves							
X	AL	6,004,865	12/99	Horiuchi, et al.							
10	AM	5,831.305	11/98	Kim	<u> </u>						
AL	AN	6,117,760	09/00	Gardner, et al.							
X	AO	6,373,138	04/02	Noble							
X	ΑP	6,274,919	10/80	Wada				<u> </u>	عبميدين		
		,		FOREIGN PATENT DOCUMENT	\$,			
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	AS	1	THER REFER	ENCES (including Author, Title, Date.	Perturus Pagas, Etc.)	 >		<u> </u>			
AT Davari et. al., 'A Variable-Size Shallow Trench Isolation (STI) Technology With Diffused Sidewall Doping For Submici								Submicron CMC	os,·		
IEDM Technical Digest, International Electron Devices Meeting, San Francisco,							8, pp. 92-	95.			
100	AU	Bakeman et. al., "A High Performance 16-Mb Dram Technology," 1990 Symposium on VLSI Technology Digess of Technical Papers.									
Ki		1990 VLS1 Tec	hnology Symp	osium, Honolulu, HI, June 4-7, 19	90, pp. 11-12.	•					
EXAMINER	EXAMINER LA GALLA SA A DATE CONSIDERED & //3 / AT (
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					U.S. PATENT DOCUMENTS							
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R	**	5,241	1,211	08/93	Tashiro							
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		•	то	ier referei	NCES (including Author, Title, Dat	le, Pertinent Pages, Et	c.)	<u> </u>				
1	AS		Suma et. al., "Ar	SOI-DRAM	With Wide Operating Voltage Rang	ge by CMOS/SIMOX	Technology,	· IEEE Journa	d of Solid-Su	ite		
Al			Circuits, November 1994, pp. 1323-1329.									
1 1	Kuge et. al., "SOI-DRAM Circuit Technologies For Low Power High Speed Multigiga Scale Memories", IEEE							ries", IEEE Io	urnal of Soli	i-Siate		
Su			Circuiu, April 1996, pp. 586-591.									
W	,		Y. Kohyama et a	al., "Buried Bit	Line Cell for 64MB DRAMs,* IEI	EE, 1990 Symposium	on VLSI Te	chnology, pp.	17, 18.			
N												
12			IBM Technical C	Disclosure Bulle	etin, "Buried Stud That Eliminates	Substrate and Well C	ontact Requ	irements",				
\mathcal{H}		Vol. 39, Pub No. 6, June 1996.										
			Takahiro Onai e	s al., "SEPIA:	A New Isolation Structure for Soft	-Error-Immune LSI's,"	1993 (EE)	2, 3 pages.				
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